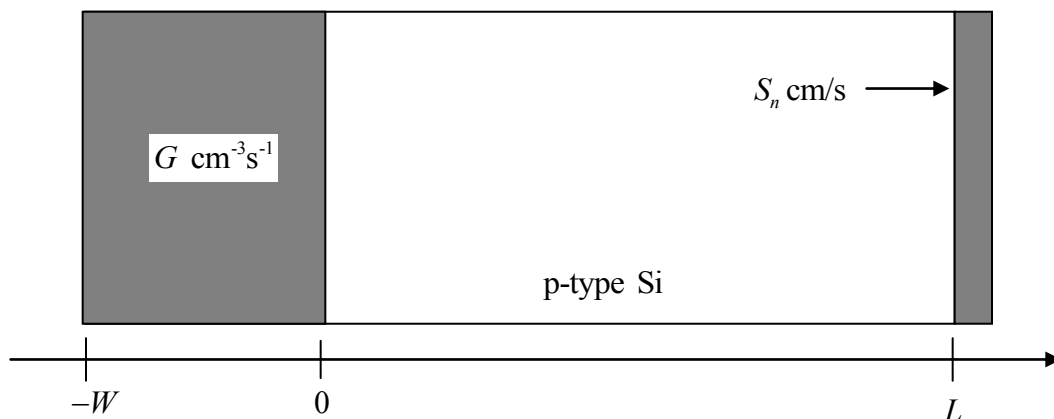


# ECE-606

Homework No. 6 Assigned: Sept. 25 Due: Oct. 2

- 1) The number of electrons and holes in Silicon undergoing radiative (light-emitting) recombination is small owing to silicon's indirect band structure. We will perform a short calculation below to convince ourselves that the indirect band gap is indeed the source of intrinsic Si not used as an opto-electronic material.
  - a. A photon of wavelength of  $10^4$  Å is incident on a piece of Silicon, assuming that the lattice constant of silicon is 5 Å; prove that the momentum carried away by the photon is much less than the change in the electron momentum.
  - b. What is the possible mechanism that would be able to carry off the large change in electron momentum? Explain briefly why this process has a very low probability of occurrence.
  - c. Draw a detailed sketch showing the various ways radiative recombination can happen in Silicon. Sketch a comparable diagram for GaAs too.
  - d. The energy of the photon given off during a radiative electron-hole recombination event in Silicon is approximately equal to 1.2 eV. Will the light emitted by this process be visible to the human eye?
- 2) Solve ASF 5.6
- 3) Solve ASF 6.1
- 4) The purpose of this exercise is to familiarize you with minority carrier diffusion in semiconductors. Recall that for a uniformly doped, p-type semiconductor with a uniform electron-hole generation rate of  $G$  electron-hole pairs / $\text{cm}^3 \cdot \text{s}$ , the excess minority carrier (electron) density is,  $\Delta n = G\tau_n$ , where  $\tau_n$  is the minority carrier lifetime.

Consider a semiconductor as shown below.



Assume that the electron-hole generation rate is  $G$  for  $x \leq 0$  and that the contact at  $x = L$  is specified by a minority carrier surface recombination velocity  $S_n$ .

- a. Assume that  $\Delta n = G\tau_n$  for  $x \leq 0$  (this is an approximation that ignores edge effects near  $x = 0$ ). Also assume that the diffusion length,  $L_n = \sqrt{D_n\tau_n} \ll L$  and that  $S_n \rightarrow \infty$ . Derive an expression for  $\Delta n(x)$  for  $x > 0$ .
  - b. Repeat part a) but this time assume that the diffusion length,  $L_n = \sqrt{D_n\tau_n} \gg L$  and that  $S_n \rightarrow \infty$ . Derive an expression for  $\Delta n(x)$  for  $x > 0$ .
  - c. Repeat part b) but now assume that  $S_n = 0$ . Derive an expression for  $\Delta n(x)$  for  $x > 0$ .
- 5) Inter-band impact generation of electron-hole pair in a high electric field is one of the many hot carrier effects. We will perform a simple calculation to estimate the equivalent electron temperature of a **hot** electron

Assume that the initial energy supplied by an energetic electron to form an electron-hole pair is  $1.5E_g$ , where  $E_g$  is the band gap of Silicon.

- a. Compute the effective electron energy at room temperature
  - b. Calculate the equivalent electron temperature  $T_{\text{electron}}$  for the electron that initiated the electron-hole pair generation
- 6) A semiconductor with band gap  $E_g$  is irradiated with photon of energy  $h\nu$ . Assuming the energy of photon is greater than the band gap, electron-hole pairs are created through direct excitation of the electrons from the valence band. Determine the wave vector  $\mathbf{k}$  and energy of the electrons and holes. The semiconductor is assumed to be direct band gap.

Your answer should be in terms of the Planck's constant,  $E_c$  (bottom of the conduction band),  $E_v$  (top of valence band), effective masses of electrons and holes at the bottom of conduction and top of valence bands respectively.